

Notice of References Cited

Application/Control No.

10/559,844

Applicant(s)/Patent Under
Reexamination
ISHIKAWA ET AL.

Examiner

Deborah Yee

Art Unit

1793

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,755,895	05-1998	Tamehiro et al.	148/336
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	08-209287	08-1996	Japan	Asahi, Hitoshi et al	-----
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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